SN54111, SN74111
DUAL J-K MASTER-SLAVE FLIP-FLOPS WITH DATA LOCKOUT

DECEMBER 1983 – REVISED MARCH 1988

- **Package Options Include Plastic and Ceramic DIPs and Ceramic Flat Packages**
- **Dependable Texas Instruments Quality and Reliability**

description

The SN54111 and SN74111 are d-c coupled, variable-skew, J-K flip-flops which utilize TTL circuitry to obtain 25-MHz performance typically. They are termed "variable-skew" because they allow the maximum clock skew in a system to be a direct function of the clock pulse width. The J and K inputs are enabled to accept data only during a short period (30 nanoseconds maximum hold time) starting with, and immediately following the rising edge of the clock pulse. After this, inputs may be changed while the clock is at the high level without affecting the state of the master. At the threshold level of the falling edge of the clock pulse, the data stored in the master will be transferred to the output. The effective allowable clock skew then is minimum propagation delay time minus hold time, plus clock pulse width. This means that the system designer can set the maximum allowable clock skew needed by varying the clock pulse width. Thus system design is made easier and the requirements for sophisticated clock distribution systems are minimized or, in some cases, entirely eliminated. These flip-flops have an additional feature-the synchronous input has reduced sensitivity to data change while the clock is high because the data need be present for only a short period of time and the system's susceptibility to noise is thereby effectively reduced.

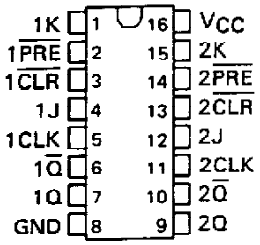
The SN54111 is characterized for operation over the full military temperature range of −55°C to 125°C; the SN74111 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE

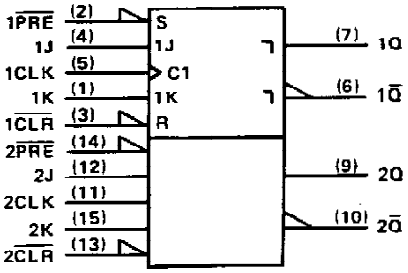
INPUTS					OUTPUTS	
$\overline{PRE}$	$\overline{CLR}$	CLK	J	K	Q	$\overline{Q}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H‡	H‡
H	H	⊓	L	L	Q_0	$\overline{Q}_0$
H	H	⊓	H	L	H	L
H	H	⊓	L	H	L	H
H	H	⊓	H	H	TOGGLE	

‡This configuration is non-stable; that is, it will not persist when preset or clear return to their inactive (high) level.

SN54111 . . . J PACKAGE
SN74111 . . . N PACKAGE
(TOP VIEW)



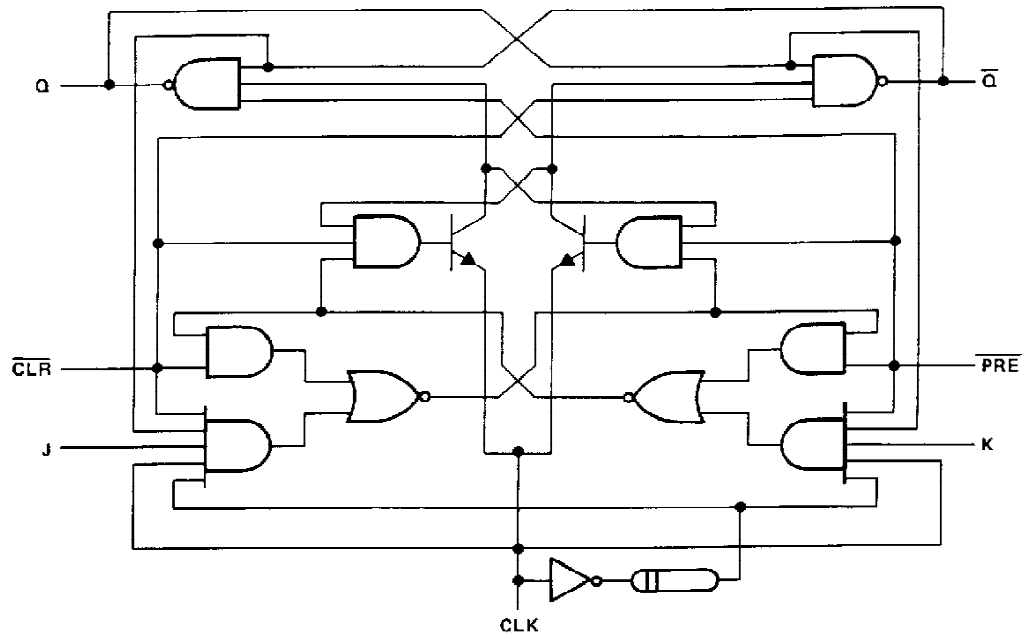
logic symbol†



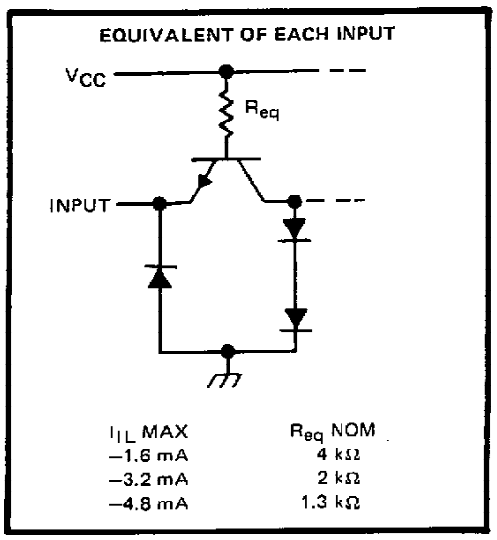
†This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

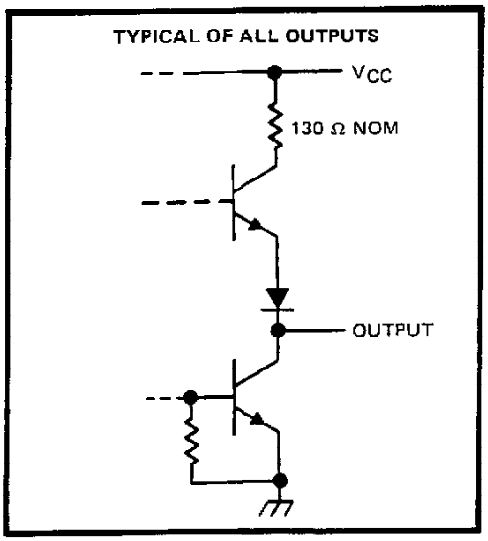
PRODUCTION DATA documents contain information current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

logic diagram (positive logic)



schematics of inputs and outputs





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V_{CC} (see Note 1) . . . . . 7 V
Input voltage . . . . . 5.5 V
Operating free-air temperature range: SN54111 . . . . . −55°C to 125°C
SN74111 . . . . . 0°C to 70°C
Storage temperature range . . . . . −65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

recommended operating conditions

			SN54111			SN74111			UNIT
			MIN	NOM	MAX	MIN	NOM	MAX	
V_{CC}	Supply voltage		4.5	5	5.5	4.75	5	5.25	V
V_{IH}	High-level input voltage		2			2			V
V_{IL}	Low-level input voltage				0.8			0.8	V
I_{OH}	High-level output current				−0.8			−0.8	mA
I_{OL}	Low-level output current				16			16	mA
t_w	Pulse duration	CLK high or low	25			25			ns
		$\overline{PRE}$ or $\overline{CLR}$ low	25			25			
t_{su}	Input setup time before CLK ↑		0			0			ns
t_h	Input hold time data after CLK ↑		30			30			ns
T_A	Operating free-air temperature		−55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS †	SN54111			SN74111			UNIT
			MIN	TYP‡	MAX	MIN	TYP‡	MAX	
V_{IK}		V_{CC} = MIN, I_I = −12 mA			−1.5			−1.5	V
V_{OH}		V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OH} = −0.8 mA	2.4	3.4		2.4	3.4		V
V_{OL}		V_{CC} = MIN, V_{IH} = 2 V, V_{IL} = 0.8 V, I_{OL} = 16 mA		0.2	0.4		0.2	0.4	V
I_I		V_{CC} = MAX, V_I = 5.5 V			1			1	mA
I_{IH}	J or K	V_{CC} = MAX, V_I = 2.4 V			40			40	μA
	$\overline{CLR}$ or $\overline{PRE}$				80			80	
	CLK				120			120	
I_{IL}	J or K	V_{CC} = MAX, V_I = 0.4 V			−1.6			−1.6	mA
	$\overline{CLR}$¶				−3.2			−3.2	
	$\overline{PRE}$¶				−3.2			−3.2	
	CLK				−4.8			−4.8	
I_{OS}§		V_{CC} = MAX	−20		−57	−18		−57	mA
I_{CC}#		V_{CC} = MAX, See Note 2		14	20.5		14	20.5	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.
‡ All typical values are at V_{CC} = 5 V, T_A = 25°C.
§ Not more than one output should be shorted at a time.
¶ Clear is tested with preset high and preset is tested with clear high.
# Average per flip-flop.
NOTE 2: With all outputs open, I_{CC} is measured with the Q and $\overline{Q}$ outputs high in turn. At the time of measurement, the clock input is at 4.5 V.

switching characteristics, V_{CC} = 5 V, T_A = 25°C (see note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	TEST CONDITIONS	MIN	TYP	MAX	UNIT
f_{max}				20	25		MHz
t_{PLH}	$\overline{PRE}$ or $\overline{CLR}$	Q or $\overline{Q}$	R_L = 400 Ω, C_L = 15 pF		12	18	ns
t_{PHL}					21	30	ns
t_{PLH}	CLK	Q or $\overline{Q}$			12	17	ns
t_{PHL}					20	30	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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